

## ESD TEST REPORT

**Field-Induced Charged-Device  
Model**
**JS-002-2018**

ANSI/ESDA/JEDEC Standard, Method JS-002-2018 is an ESD test using Field-Induced Charged-Device Model, three positive and three negative pulses applied to the devices per customer's specification with 0.5 second cool down between pulses.

**Customer :**                    **Alpha & Omega Semiconductor (Shanghai), Ltd.**

**Address:**                    Building 8 & 9, No. 91, Lane 109, Rong Kang Road,  
                                       Songjiang Export Processing Zone, Zone B, # 888 Song Zheng Highroad, Shanghai

**Device Information**

Part No. :	AOCA33102E	Sample Size :	3pcs
Package Type :	AlphaDFN3X2.74-14L	Pin Count :	14
Lot No. :	0B06	Date Code :	-
VDD Domains :	S2 S1	VSS Domains :	S1 S2

**Test Equipment**

Tester1 :	ZAPMASTER MK.2 SE	Serial No. :	0508317
Calibration Date :	Jan 15 <sup>th</sup> 2020	Expiration Date :	Jan 14 <sup>th</sup> 2021
Tester2 :	Orion Robotic CDM Test System	Serial No. :	0806294
Calibration Date :	Jan 16 <sup>th</sup> 2020	Expiration Date :	Jan 15 <sup>th</sup> 2021

**Environmental Condition**

Temperature :	23°C	Humidity :	30% RH
Submit date :	Nov 23 <sup>rd</sup> 2020	Complete date :	Nov 24 <sup>th</sup> 2020

### Stress Summary

CDM			
Sample No.	Voltage Level	Process	Spot Test Results* (Within 10µA @ 8V between G and S2/S1)
9#	±2kV	All Pins Done	PASS
10#		All Pins Done	PASS
11#		All Pins Done	PASS

### Test Result\*

Model	Pin Combinations	ESD Sensitivity Pass*: <b>2kV</b>	V Class: <b>C3</b>
CDM	ALL PINS DONE	±2kV	JS-002-2018 Class C0a: <125V Class C0b: 125V to <250V Class C1: 250 to <500 V Class C2a: 500 to <750 V Class C2b: 750 to <1000 V Class C3: ≥1000V

\*Note: Results will be updated based on customer final electrical test results.

Test Engineer: Fei Teng	Date: Nov 24 <sup>th</sup> 2020
Approved by FA Manager: 	Date: Nov 24 <sup>th</sup> 2020



### Recommendations

**EAG Shanghai** certifies that above tests have been performed in accordance to the requirements stated above and per the customer purchase order and applicable documents.

**EAG Shanghai** recommends electrical testing as a validation of reported results. Curve Trace criteria was utilized to specify a pass or fail. Industry standards require the device to be tested functionally at post stress and should continue to meet all electrical parameters as per the data sheet.

**This report** can not be duplicated in part, without the permission of EAG Shanghai. This report refers only to the specimen(s) submitted to test, and is invalid if used separately. This report is only valid with the examination seal and signature of EAG Shanghai. The tested specimen(s) will only be preserved for thirty days form the date issued, if not collected by the applicant. If discrepancies exist about report, please put forward within one week.